

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10519988	SCHARNWEBER ET AL.
<b>Examiner</b>	<b>Art Unit</b>	
Young J Kim	1637	

### SEARCHED

Class	Subclass	Date	Examiner

### SEARCH NOTES

Search Notes	Date	Examiner
Patent Databases (USPT, USPPGP, EPO, JPO, DERWENT, IBM-TDB)	2/27/2008	YJK
see enclosed for text-search strategy	2/27/2008	YJK
Patent Databases (USPT, USPPGP, EPO, JPO, DERWENT, IBM-TDB)	12/10/2008	/YJK/
see enclosed for text-search strategy	12/10/2008	/YJK/

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner

	/Young J Kim/ Primary Examiner, Art Unit 1637
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